

Notice of References Cited	Application/Control No. 10/601,732		Applicant(s)/Patent Under Reexamination XIONG ET AL.	
	Examiner Nhon T. Diep		Art Unit 2621	Page 1 of 1

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*	C	US-2003/0053708	03-2003	Kryukov et al.	382/261
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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